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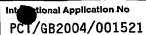
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INTERNATIONAL SEARCH REPORT

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(PCT Article 18 and Rules 43 and 44)

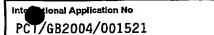
Applicant's or agent's file reference	FOR FURTHER	see Form PCT/ISA/220
P3159 WO ORD	ACTION	s well as, where applicable, item 5 below.
International application No.	International filing date (day/month/yea	(Earliest) Priority Date (day/month/year)
PCT/GB2004/001521	08/04/2004	09/04/2003
Applicant		
AOTI OPERATING COMPANY, II	NC.	
This International Search Report has been according to Article 18. A copy is being tra	n prepared by this international Searchin ansmitted to the international Bureau.	g Authority and is transmitted to the applicant
This International Search Report consists	of a total of sheets.	
It is also accompanied by	a copy of each prior art document cited	in this report.
Basis of the report a. With regard to the language, the language in which it was filed, un	international search was carried out on t less otherwise indicated under this item.	the basis of the international application in the
The international this Authority (Ru		translation of the international application furnished t
b. With regard to any nucle	otide and/or amino acid sequence dis	closed in the international application, see Box No. I.
2. Certain claims were fou	ind unsearchable (See Box II).	
3. Unity of invention is lac	eking (see Box III).	
4. With regard to the title,		
, <u> </u>	ubmitted by the applicant.	
·	shed by this Authority to read as follows:	
DETECTION METHOD AND	APPARATUS METAL PARTICUL	ATES ON SEMICONDUCTORS
5. With regard to the abstract,		
	ubmitted by the applicant.	and the second second
the text has been establi may, within one month fr	shed, according to Rule 38.2(b), by this com the date of mailing of this internation	Authority as it appears in Box No. IV. The applicant al search report, submit comments to this Authority.
6. With regards to the drawings ,		
1	published with the abstract is Figure No.	. <u>4A</u>
as suggested by	the applicant. This Authority, because the applicant faile	d to suggest a figure.
	his Authority, because the applicant lailer his Authority, because this figure better o	
]	be published with the abstract.	



A. CLASSIFICATION OF SUBJECT MATTER
IPC 7 G01N21/64 G01N21/95 G01R31/265 According to International Patent Classification (IPC) or to both national classification and IPC B. FIELDS SEARCHED Minimum documentation searched (classification system followed by dassification symbols) GO1N GO1R Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched Electronic data base consulted during the international search (name of data base and, where practical, search terms used) EPO-Internal, PAJ C. DOCUMENTS CONSIDERED TO BE RELEVANT Relevant to claim No. Citation of document, with indication, where appropriate, of the relevant passages Category ° WO 02/29883 A (HIGGS VICTOR; AOTI 1-19 X OPERATING COMPANY INC (US)) 11 April 2002 (2002-04-11) page 16 -page 18; figure 5 1 - 19WO 02/077621 A (HIGGS VICTOR ; AOTI Α OPERATING COMPANY INC (US)) 3 October 2002 (2002-10-03) page 6 -page 8; claims 2,3 page 14 -page 16 1-19 PATENT ABSTRACTS OF JAPAN Α vol. 2003, no. 06, 3 June 2003 (2003-06-03) & JP 2003 045928 A (SHIN ETSU HANDOTAI CO LTD), 14 February 2003 (2003-02-14) abstract; figure 9 -/--Patent family members are listed in annex. Further documents are listed in the continuation of box C. Special categories of cited documents: "T" later document published after the international filing date or priority date and not in conflict with the application but dited to understand the principle or theory underlying the "A" document defining the general state of the art which is not considered to be of particular relevance invention "E" earlier document but published on or after the international "X" document of particular relevance; the claimed invention cannot be considered novel or cannot be considered to involve an inventive step when the document is taken alone "L" document which may throw doubts on priority claim(s) or which is cited to establish the publication date of another citation or other special reason (as specified) document of particular relevance; the claimed invention cannot be considered to involve an inventive step when the document is combined with one or more other such documents, such combination being obvious to a person skilled in the art. *O* document referring to an oral disclosure, use, exhibition or in the art "P" document published prior to the international filing date but later than the priority date claimed *&* document member of the same patent family Date of mailing of the International search report Date of the actual completion of the international search 22/07/2004 14 July 2004 Authorized officer Name and mailing address of the ISA European Patent Office, P.B. 5818 Patentlaan 2 NL - 2280 HV Rijswijk Tel. (+31-70) 340-2040, Tx. 31 651 epo nl, Fax: (+31-70) 340-3016 Mason, W

Internal Application No PCT/GB2004/001521

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